## Product Change Notification - JAON-23USEG246

**Date:** 26 Aug 2015

Product Category: Supertex

Notification subject: CCB 1409.116 Final Notice: Qualification of 8060T die attach material for Supertex

products in 3L SOT-89 package at CRTK assembly site.

Notification text: PCN Status:

Final notification

## **Microchip Parts Affected:**

Please open the attachments found in the attachments field below labeled as PCN\_#\_Affected\_CPN.

NOTE: For your convenience Microchip includes identical files in two formats (.pdf and .xls).

# **Description of Change:**

Qualification of 8060T die attach material for Supertex products in 3L SOT-89 package at CRTK assembly site.

# Pre Change:

Assembled at CRTK using 8600 die attach material

## **Post Change:**

Assembled at CRTK using 8060T die attach material

## Impacts to Data Sheet:

No

## Reason for Change:

To improve productivity as part of the integration of Supertex and Microchip.

#### **Change Implementation Status:**

Complete

#### **Estimated First Ship Date:**

August 27, 2015 (date code: 1535)

NOTE: Please be advised that after the estimated first ship date customers may receive pre and post change parts.

#### Markings to Distinguish Revised from Unrevised Devices:

Traceability code

## **Revision History:**

August 26, 2015: Issued final notification

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

Attachment(s):

PCN JAON-23USEG246 Qual Report.pdf PCN JAON-23USEG246 Affected CPN.pdf PCN JAON-23USEG246 Affected CPN.xls

Please contact your local Microchip sales office with questions or concerns regarding this notification.

#### **Terms and Conditions:**

If you wish to change your product/process change notification (PCN) profile please log on to our website at <a href="http://www.microchip.com/PCN">http://www.microchip.com/PCN</a> sign into myMICROCHIP to open the myMICROCHIP home page, then select a profile option from the left navigation bar.

To opt out of future offer or information emails (other than product change notification emails), click here to go to <u>microchipDIRECT</u> and login, then click on the "My account" link, click on "Update profile" and un-check the box that states "Future offers or information about Microchip's products or services."

DCM IAON 22USEC246
PCN_JAON-23USEG246
CATALOG_PART_NBR
CL1N8-G
CL25N8-G
CL2N8-G
DN1509N8-G
DN2450N8-G
DN2530N8-G
DN2540N8-G
DN3135N8-G
DN3145N8-G
DN3525N8-G
DN3535N8-G
DN3545N8-G
DN3545N8-G-D561
FP0100N8-G
HV9921N8-G
HV9922N8-G
HV9923N8-G
LND150N8-G
LR645N8-G
LR745N8-G
LR8N8-G
MD0100N8-G
TN0104N8-G
TN2425N8-G
TN2435N8-G
TN2501N8-G
TN2504N8-G
TN2510N8-G
TN2510N8-G-D592
TN2524N8-G
TN2540N8-G
TN2540N8-L-G
TN5325N8-G
TN5335N8-G
TP2424N8-G
TP2435N8-G
TP2502N8-G
TP2510N8-G
TP2520N8-G
TP2522N8-G
TP2540N8-G
TP2540N8-L-G
TP5322N8-G
VN2450N8-G
VN2460N8-G

VN3205N8-G
VN3205N8-G-D576
VP2450N8-G
VP3203N8-G



# **QUALIFICATION REPORT**RELIABILITY LABORATORY

PCN #: JAON-23USEG246

Date **July 29, 2015** 

Qualification of 8060T die attach material for Supertex products in 3L SOT-89 package at CRTK assembly site.



Purpose Qualification of 8060T die attach material for Supertex products in 3L SOT-89

package at CRTK assembly site.

Part No. TN5325N8-G

**Lot No.** CRTK154600014.000

**CCB No.** 1409.116

**Package** 

Type 3L SOT-89

**Die thickness** 7.5 mils

**Die size** 55.9 x 29.9 mils

**Lead Frame** 

Paddle size 70 x 75 mils

Material PMC90

Part Number ST89MTX-2-L

Die attach material

Epoxy (Silver paste) 8060T

Wire Au

Mold Compound EME-G600

Plating Composition Ag

#### **TEST 1: ASSEMBLY PROCESS CHARACTERIZATION**

TEST	RESPONSIBLE	METHOD	CONDITION	ACCEPTANCE_CRITERIA	A_SS	RESULT
Die Shear	Subcon	MIL-STD-883J- M2019.9	NA	min strength & evident of adhesion conform to MILSTD-883J-M2019.9	0 / 32 units	PASS
DA Bondline Thickness	Subcon	to subcon's spec	Epoxy Cured	BLT (Dry) Control 0.6 ~ 0.9 mil	0 / 5 units	PASS
Bond Shear	Subcon	JESD22-B116A	NA	and a min strength conform to JESD22-B116A; and     ball bond dia shall be reported	0 / 30 bonds from min 5 units	PASS
Wire Bond Pull	Subcon	MIL-STD-883J- M2011.9	Cond C or D	min strength conform to MIL-STD-883J- M2011.9	0 / 30 bonds from min 5 units	PASS
X-Ray	Subcon	X-Ray	NA	Wire and die condition to subcon spec	0 / 1 shot	PASS
Terminal Plating Thickness	Subcon	XRF or else	NA	300 - 1000 micro-inch	0 / 5 units	PASS
Terminal Plating / Solder Ball Material	Subcon	XRF, RoHS report or else	NA	Pb-free	0 / 5 units	PASS

#### **TEST 2: FINAL TEST**

TEST		RESPONSIBLE	METHOD	CONDITION	ACCEPTANCE_CRITERIA	A_SS	RESULT
Post-A Test Y	Assembly Final rield	MTAI	per device spec	NA	per device spec	>85%	PASS

#### **TEST 3: PACKAGE INTEGRITY AND MECHANICAL TEST**

TEST	RESPONSIBLE	METHOD	CONDITION	ACCEPTANCE_CRITERIA	A_SS	RESULT
External Visual	MTAI	Supertex spec# QCGP-8001	to Supertex spec# QCGP-8001	visual defect to Supertex spec# QCGP-8001	0 / 315 units	PASS
Physical Dimension	MTAI	JESD22-B100B	post-assembly	conform to Supertex spec# DSPD- 3TO243AAN8	0 / 8 units	PASS
Solderability (Tin-alloy)	MTAI	JESD22-B102E	1) Condition C (Tin-alloy): 8hrs steam age; 2) Test Method 1: Dip & Look Test; 3) Group 1: test to SnPb solder (215 +/-5 C); Group 2: test to Pb-free solder (245 +/-5 C)	min 95% coverage on critical area	0 / 8 units for Group 1; 0 / 8 units for Group 2	PASS

#### **TEST 4: RELIABILITY AND LIFE TEST**

TEST	RESPONSIBLE	METHOD	CONDITION	ACCEPTANCE_CRITERIA	A_SS	RESULT
MSL Pre-Conditioning	MTAI	JESD22-A113F	MSL 1 @ 260 +5/-0C Pb-free reflow	1) no pkg crack; and 2) electrical pass; and 3) 25 units (i.e. unit#1-25) for pre- & post- stress T- / CSAM shall be reported 4) reflow profile plot shall be reported	0 / 250 units	PASS
AutoClave	MTAI	JESD22-A102D	1) for SMD, MSL pre-conditioned prior to test 2) 121C / 100%RH / 15PSIG / 168hrs	electrical pass	0 / 45 units	PASS
Thermal Shock	MMT	MIL-STD-883J- M1011.9	1) for SMD, MSL pre-conditioned prior to test 2) Cond B: -55 to 125C / 200 cyc	electrical pass	0 / 45 units	PASS
Temperature Cycling	MTAI	MIL-STD-883J- M1010.8	1) for SMD, MSL pre-conditioned prior to test 2) Cond C: -65 to 150C / 500 cyc	electrical pass	0 / 45 units	PASS
Temperature Humidity Bias (THB)	SVDC / MTAI	JESD22-A101C	1) for SMD, MSL pre-conditioned prior to test 2) biased @85C / 85%RH for 168 / 500 / 1000hrs	electrical pass	0 / 45 units	PASS